	Tomographic and In-Situ Characterization in Electron Microscopy		
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	Summary		
	This symposium aims to address forefront scientific and technological developments in the field of electron microscopy (EM). Exciting new developments are currently occuring in the areas of three-dimensional (3D) EM and in-situ EM. 3D EM subjects include cryo EM, phase-plate technology for 3D imaging, analytical and scanning transmission electron microscopy (STEM) tomography, aberration corrected 3D EM, focused ion beam (FIB) sectioning combined with scanning electron microscopy (SEM). This symposium will also explore novel computational approaches for 3D reconstruction, segmentation, and visualization. In-situ EM aims to study materials under close to realistic conditions. Topics include the (sub-)nanoscale study of biological samples and functional materials in, for example, gaseous environments, at elevated temperatures, in electric fields, under mechnical stress, or in liquid. It will be discussed how processes can be studied by including the time domain in electron microscopy.		